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SERIAL NO. / 08/961,929 FORM PTO-1449 (Modified) ATTY. DOCKET NO. BU9-96-041 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION APPLICANT: DISCLOSURE STATEMENT Conrad et al. FILING DATE: GROUP: (Use several sheets if necessary) U.S. PATENT DOCUMENTS REFERENCE DESIGNATION **EXAMINER** DOCUMENT FILING DATE SUBCLASS INITIALS NUMBER DATE NAME CLASS (IF APPRO.) 2/27/79 12/19/97 14 17 î Kleinknecht et al. AΒ 10/11/83 Kleinknecht et al. /11/86 AC 11/17/87 Lindow et al. ΑĎ 5/31/88 Lindow et al. 7/3/85 ΑE 8/27/91 3/17/89 Greenberg et al. AF 11/17/92 McNeil et al. 2/27/91 AG 9/20/94 DeGroot, Peter 8/7/92 AΗ 11/8/94 Mack, Chris 7/29/93 6/3/86 6/4/84 Fridge et al. FOREIGN PATENT DOCUMENTS DOCUMENT NUMBER TRANSLATION DATE COUNTRY **CLASS** SUBCLASS YES NO wo 12/19/85 AM 7/92 12/18/84 ΑO OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.) Diffraction Analysis of Dielectric Surface-relief Gratings, M. G. Moharam and T. K. Gaylord, Vol. 72, No ΑO 10/Oct.1982/J. Opt. Soc. Am. pp1385-1392 Formulation for Stable and Efficient Implementation of the Rigorous Coupled-wave Analysis of Binary Gratings, M. AR G. Moharam, Eric B. Grann, and Drew A. Pommet, Vol. 12, No. 5/May 1995/ J. Opt. Sog. Am. pp1069-1076 Linewidth Measurement of Gratings on Photomasks: A Simple Technique, S. Sohail H. Haqvi, Susan Gaspar, Kirt Hickman, Ken Biship, and John R. McNeil, 4/1/92/Vol. 32, No. 10/Applied Optigs pp 1377-1384 DATE CONSIDERED **EXAMINER** 12/3/98

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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